

Title (en)

QUANTITATIVE IMAGING OF DIELECTRIC PERMITTIVITY AND TUNABILITY

Title (de)

QUANTITATIVE ABBILDUNG DER DIELEKTRIZITÄTSKONSTANTE UND DER ABSTIMMBARKEIT

Title (fr)

REPRESENTATION QUANTITATIVE PERMETTANT DE MESURER DES PROPRIETES DE PERMITTIVITE ET D'ACCORDABILITE DE DIELECTRIQUES

Publication

EP 1212625 A1 20020612 (EN)

Application

EP 00920123 A 20000405

Priority

- US 0008943 W 20000405
- US 15335499 P 19990910
- US 19190300 P 20000324

Abstract (en)

[origin: WO0120352A1] A near-field scanning microwave microscope images the permittivity and dielectric tunability of bulk and thin film dielectric samples on a length scale of about 1 micron or less. The microscope is sensitive to the linear permittivity, as well as to nonlinear dielectric terms, which can be measured as a function of an applied electric field. A versatile finite element model is used for the system, which allows quantitative results to be obtained. The technique is non destructive and has broadband (0.1-50 GHz) capability.

IPC 1-7

G01R 27/26

IPC 8 full level

G01N 22/00 (2006.01); **G01Q 30/06** (2010.01); **G01Q 40/00** (2010.01); **G01Q 60/00** (2010.01); **G01Q 60/18** (2010.01); **G01R 27/26** (2006.01)

CPC (source: EP)

B82Y 15/00 (2013.01); **G01R 27/26** (2013.01); **G01R 27/2664** (2013.01)

Citation (search report)

See references of WO 0120352A1

Designated contracting state (EPC)

AT BE CH CY DE DK ES FI FR GB GR IE IT LI LU MC NL PT SE

DOCDB simple family (publication)

WO 0120352 A1 20010322; AU 4070900 A 20010417; EP 1212625 A1 20020612; JP 2003509696 A 20030311

DOCDB simple family (application)

US 0008943 W 20000405; AU 4070900 A 20000405; EP 00920123 A 20000405; JP 2001523885 A 20000405